Detecting the surface spin state polarization of topological materials with resonant X-ray reflectometry

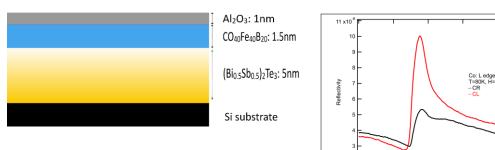
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 $\Theta = 20^{\circ}$



Applied magnetic field

